## **SHOULDER**

规格书编号 SPEC NO:

# 产品规格书 SPECIFICATION

CUSTOMER 客户:		
PRODUCT 产品:	SAW FILTER	
MODEL NO 型 号:	HDF755A3F11	
PREPARED 编 制:	CHECKED 审 核:	
APPROVED 批 准:	D A T E 日 期:	2006-5-11

客户确认 CUSTOMER RECEIVED:			
审核 CHECKED	批准 APPROVED	日期 DATE	

### 无锡市好达电子有限公司 Shoulder Electronics Limited

# SAW FILTER

#### HDF755A3 F11

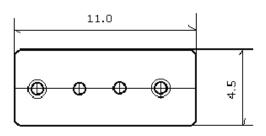
### 更改历史记录 History Record

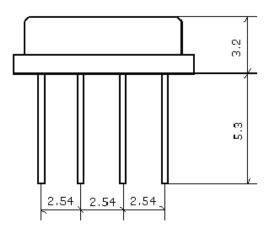
更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark

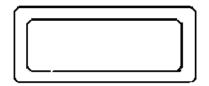
# SAW FILTER

#### HDF755A3 F11

### **1.Package Dimension**







### 2. Marking

#### HDF755A

- 1.Color: Black or Blue
- 2.755: Center Frequency(MHz)

#### **3.Performance**

3.1Application Low-Loss SAW Filter of cordless system. Center Frequency:755 MHz

# SAW FILTER

#### HDF755A3 F11

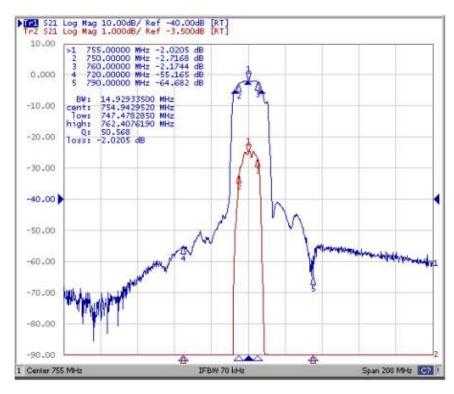
#### 3.2Maximum Rating

U	
Operation Temperature Range	-40°C to +85°C
Storage Temperature Range	-45°C to +85°C
DC. Permissive Voltage	0 V DC. max.
Maximum Input Power	5dBm

#### **3.3Electronic Characteristics**

	Unit	Minimum	Typical	Maximum
Center Frequency	MHz	<u> </u>	755	-
Insertion Loss (750~760MHz)	dB		2.2	5.0
Amplitude Ripple (750~760MHz)	dB		0.5	2.5
VSWR(750~760MHz)			1.5	
Relative Attenuation			2	5
0~720 MHz	dB	40	55	-
790~1300MHz		40	55	
Input/Output Impedance	Ohms		50	č.

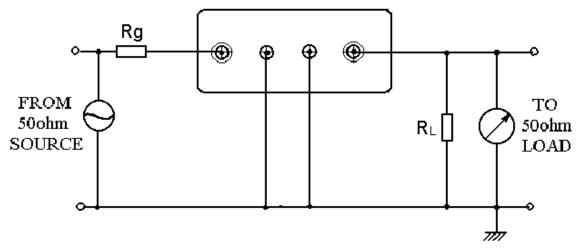
#### 3.4 Frequency Characteristics



#### HDF755A3 F11

# SAW FILTER

3.5 Test Circuit



### 4. ENVIRONMENTAL CHARACTERISTICS

4-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 3.3.

4-2 Low temperature exposure

Subject the device to  $-40^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 3.3.

4-3 Temperature cycling

Subject the device to a low temperature of  $-40^{\circ}$ C for 30 minutes. Following by a high temperature of  $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 3.3.

4-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}$ C  $\pm 10^{\circ}$ C for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 3.3.

4-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}$ C  $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 3.3.

4-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. The device shall fulfill the specifications in 3.3.

4-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 3.3.



#### **5. REMARK**

#### 5.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

#### 5.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

#### 5.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.